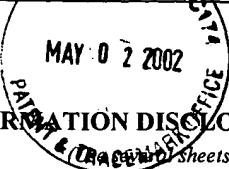


FORM PTO-1449 (REV.7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. 851763.424	APPLICATION NO. 10/061,949
 INFORMATION DISCLOSURE STATEMENT <small>(Use additional sheets if necessary)</small>				APPLICANT Amedeo La Scala	
				FILING DATE January 31, 2002	GROUP ART UNIT 2182

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
AA	5,519,713	05/21/96	Baeg et al.	371	22.1	
AB	5,812,562	09/22/98	Baeg	371	22.31	
AC	6,028,983	02/22/00	Jaber	395	183.06	
AD						
AE						
AF						
AG						
AH						
AJ						
AJ						

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
				YES	NO
AK					
AL					
AM					
AN					
AO					

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

AP	Whetsel, L., "An IEEE 1149.1 Based Test Access Architecture For ICs with Embedded Cores," <i>International Test Conference</i> , New York, November 1, 1997, pp. 69-78.
AQ	
AR	

EXAMINER	DATE CONSIDERED
	4 - SEPTEMBER 2003

* EXAMINER: Initial if reference considered, whether or not criteria is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant(s).